

AUIRLR2703

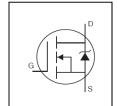
HEXFET® Power MOSFET

Features

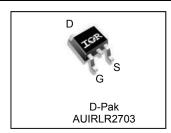
- Advanced Planar Technology
- · Logic Level Gate Drive
- Low On-Resistance
- Dynamic dV/dT Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- · Repetitive Avalanche Allowed up to Tjmax
- · Lead-Free, RoHS Compliant
- Automotive Qualified *

Description

Specifically designed for Automotive applications, this cellular design of HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of other applications.



V _{DSS}	30V
R _{DS(on)} max.	45mΩ
D (Silicon Limited)	23A
D (Package Limited)	20A



G	D	S
Gate	Drain	Source

Base next number Baskage Type		Standard Pack		Orderable Part Number	
Base part number	Package Type	Form	Quantity	Orderable Part Number	
ALUDI DOZOS	D. Dok	Tube	75	AUIRLR2703	
AUIRLR2703	D-Pak	Tape and Reel Left	3000	AUIRLR2703TRL	

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	23	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	16	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	20	A
I _{DM}	Pulsed Drain Current ①	96	
P _D @T _C = 25°C	Maximum Power Dissipation	45	W
	Linear Derating Factor	0.30	W/°C
V_{GS}	Gate-to-Source Voltage	± 16	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	77	ml
E _{AS (tested)}	AS (tested) Single Pulse Avalanche Energy (tested Value) ©		— mJ
I _{AR} Avalanche Current ①		14	Α
E _{AR}	Repetitive Avalanche Energy ①	4.5	mJ
dv/dt Peak Diode Recovery®		5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol	Symbol Parameter		Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		3.3	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ∅		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

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^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	30			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.030		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)} Static Drain-to-Source On-Resistance			0.045		V _{GS} = 10V, I _D = 14A ④	
	Static Drain-to-Source On-Resistance			0.065	Ω	V _{GS} = 4.5V, I _D = 12A ④
$V_{GS(th)}$	Gate Threshold Voltage	1.0			V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
gfs	Forward Trans conductance	6.4			S	V _{DS} = 25V, I _D = 14A ⑦
1	Drain to Source Leakage Current			25	μA	$V_{DS} = 30V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
1	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 16V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	ПА	V _{GS} = - 16V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Total Gate Charge			15		I _D = 14A
Gate-to-Source Charge			4.6	nC	$V_{DS} = 24V$
Gate-to-Drain Charge			9.3		V _{GS} = 4.5V ④⑦
Turn-On Delay Time		8.5			V _{DD} = 15V
Rise Time		140		no	I _D = 14A
Turn-Off Delay Time		12		115	$R_G = 12\Omega, V_{GS} = 4.5V$
Fall Time		20			$R_D = 1.1\Omega \oplus \emptyset$
Internal Drain Inductance		4.5			Between lead, 6mm (0.25in.)
Internal Source Inductance		7.5			from package and center of die contact
Input Capacitance		450			$V_{GS} = 0V$
Output Capacitance		210		pF	V _{DS} = 25V
Reverse Transfer Capacitance		110			<i>f</i> = 1.0MHz⑦
	Gate-to-Source Charge Gate-to-Drain Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance Output Capacitance	Gate-to-Source Charge — Gate-to-Drain Charge — Turn-On Delay Time — Rise Time — Turn-Off Delay Time — Fall Time — Internal Drain Inductance — Internal Source Inductance — Input Capacitance — Output Capacitance —	Gate-to-Source Charge — — Gate-to-Drain Charge — — Turn-On Delay Time — 8.5 Rise Time — 140 Turn-Off Delay Time — 12 Fall Time — 20 Internal Drain Inductance — 4.5 Internal Source Inductance — 7.5 Input Capacitance — 450 Output Capacitance — 210	Gate-to-Source Charge — 4.6 Gate-to-Drain Charge — 9.3 Turn-On Delay Time — 8.5 — Rise Time — 140 — Turn-Off Delay Time — 12 — Fall Time — 20 — Internal Drain Inductance — 4.5 — Internal Source Inductance — 7.5 — Input Capacitance — 450 — Output Capacitance — 210 —	Gate-to-Source Charge — — 4.6 nC Gate-to-Drain Charge — — 9.3 Turn-On Delay Time — 8.5 — Rise Time — 140 — Turn-Off Delay Time — 12 — Fall Time — 20 — Internal Drain Inductance — 4.5 — Internal Source Inductance — 7.5 — Input Capacitance — 450 — Output Capacitance — 210 — pF

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			226		MOSFET symbol
I _S	(Body Diode)			23 ⑤	^	showing the
	Pulsed Source Current			06	Α	integral reverse
I _{SM}	(Body Diode) ①			96		p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 14A, V_{GS} = 0V $
t _{rr}	Reverse Recovery Time		65	97	ns	$T_J = 25^{\circ}C$, $I_F = 14A$
Q_{rr}	Reverse Recovery Charge		140	210	nC	di/dt = 100A/µs④⑦
t _{on}	Forward Turn-On Time	Intrinsi	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $^{\circ}$ V_{DD} =15V,Starting T_J = 25°C, L = 570 μ H, R_G = 25 Ω , I_{AS} = 14A (See fig. 12)
- $\label{eq:local_local_local_local} \ensuremath{\Im} \quad I_{SD} \leq 14A, \ di/dt \leq 140A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ}C.$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- © Calculated continuous current based on maximum allowable junction temperature. Package limitation current = 20A.
- © This is applied for I-PAK, LS of D-PAK is measured between lead and center of die contact.
- ② Uses IRL2703 data and test conditions.



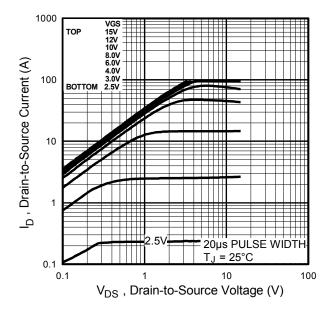


Fig. 1 Typical Output Characteristics

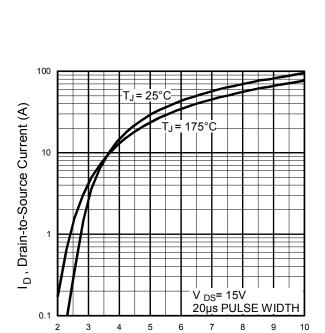


Fig. 3 Typical Transfer Characteristics

V_{GS} , Gate-to-Source Voltage (V)

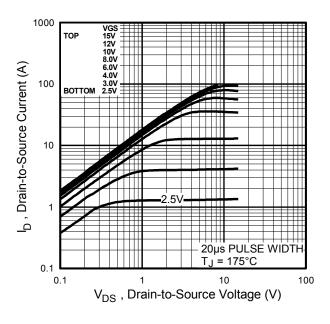


Fig. 2 Typical Output Characteristics

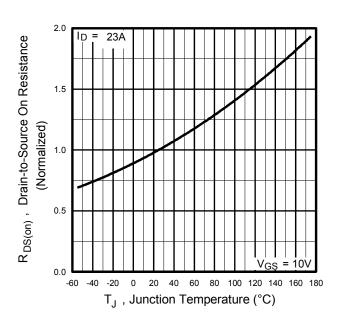


Fig. 4 Normalized On-Resistance Vs. Temperature



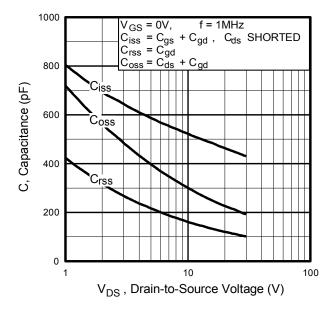


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

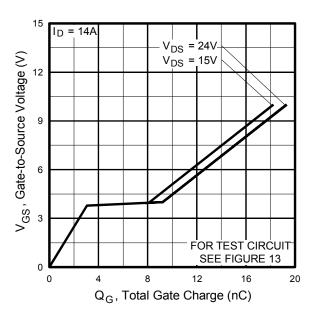


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

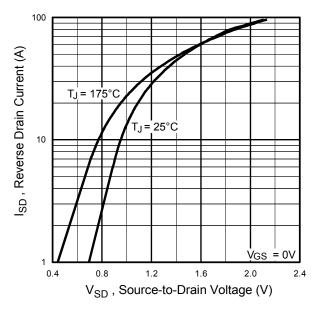


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

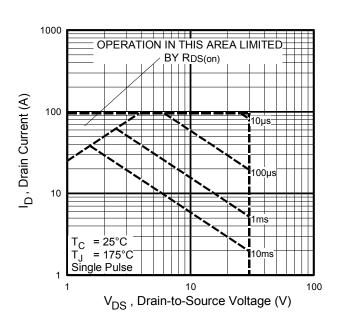


Fig 8. Maximum Safe Operating Area

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4



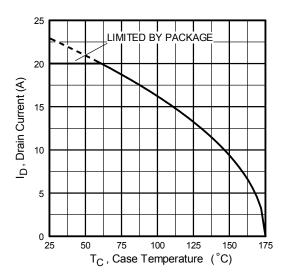


Fig 9. Maximum Drain Current Vs. Case Temperature

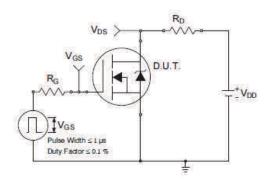


Fig 10a. Switching Time Test Circuit

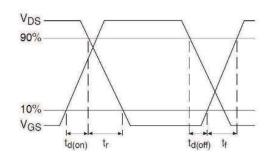


Fig 10b. Switching Time Waveforms

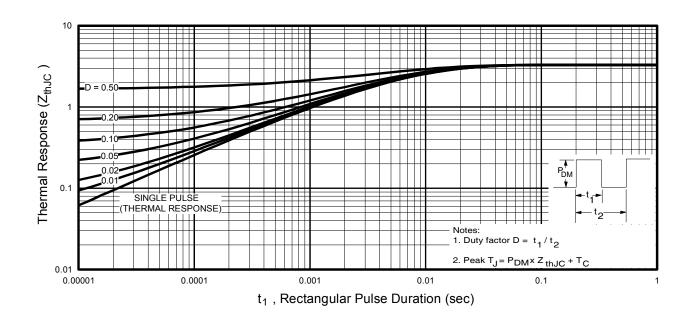


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



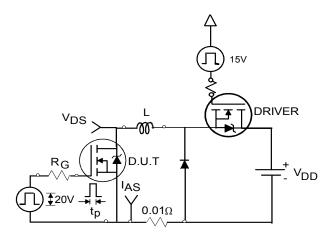


Fig 12a. Unclamped Inductive Test Circuit

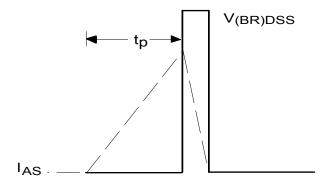


Fig 12b. Unclamped Inductive Waveforms

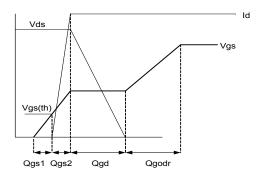


Fig 13a. Gate Charge Waveform

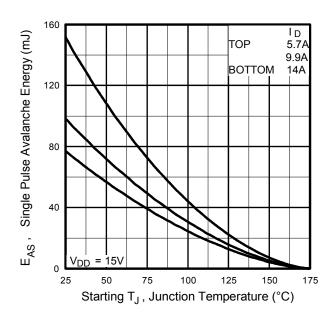


Fig 12c. Maximum Avalanche Energy vs. Drain Current

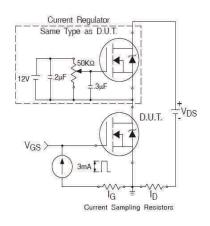
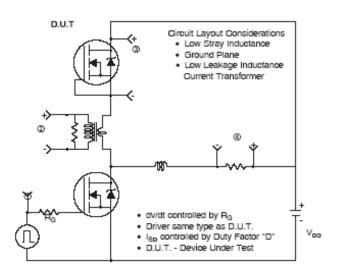
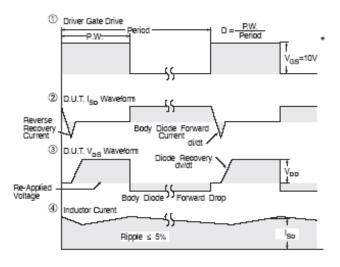


Fig 13b. Gate Charge Test Circuit



Peak Diode Recovery dv/dt Test Circuit



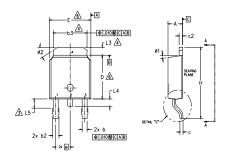


^{*} V_{GS} = 5V for Logic Level Devices

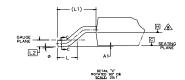
Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

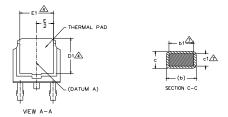


D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- Limension D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION 61 & c1 APPLIED TO BASE METAL ONLY.
- ♠ DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S					N	
Y M	DIMENSIONS					
B	MILLIM	ETERS	INC	HES	O T E S	
L	MIN.	MAX.	MIN.	MAX.	S	
Α	2.18	2.39	.086	.094		
A1	-	0.13	-	.005		
b	0.64	0.89	.025	.035		
ь1	0.65	0.79	.025	.031	7	
b2	0.76	1.14	.030	.045		
b3	4.95	5.46	.195	.215	4	
С	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	7	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	6	
D1	5.21	-	.205	-	4	
Ε	6.35	6.73	.250	.265	6	
E1	4.32	-	.170	-	4	
e	2.29	BSC	.090	BSC		
Н	9.40	10.41	.370	.410		
L	1.40	1.78	.055	.070		
L1	2.74	BSC	.108	REF.		
L2	0.51	BSC	.020	BSC		
L3	0.89	1.27	.035	.050	4	
L4	-	1.02	-	.040		
L5	1.14	1.52	.045	.060	3	
ø	0,	10*	0,	10°		
ø1	0,	15*	0,	15*		
ø2	25*	35°	25*	35*		

LEAD ASSIGNMENTS

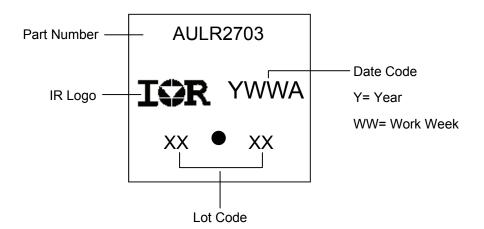
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE 4.- DRAIN

IGBT & CoPAK

- 1.- GATE
- 2.- COLLECTOR
- 3.- EMITTER
- 4.- COLLECTOR

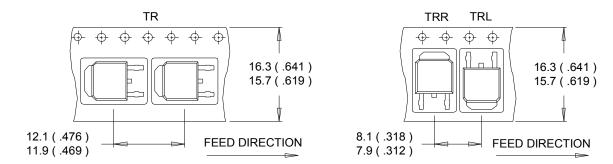
D-Pak (TO-252AA) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

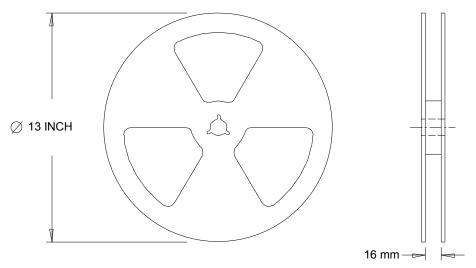


D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

		T					
		Automotive					
		(per AEC-Q101)					
Qualificat	tion Level	Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.					
Moisture Sensitivity Level D-Pak MSL1							
Marabia - Marabal	Class M2 (+/- 150V) [†]						
	Machine Model	AEC-Q101-002					
FOR	Liverage Dady Madal	Class H1A (+/- 500V) †					
ESD	Human Body Model	AEC-Q101-001					
	Charried Davies Medal	Class C5 (+/- 2000V) [†]					
Charged Device Model		AEC-Q101-005					
RoHS Co	S Compliant Yes						

[†] Highest passing voltage.

Revision History

Date	Comments		
12/11/2015	Updated datasheet with corporate template		
12/11/2015	Corrected ordering table on page 1.		

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